

**Notice of References Cited**

Application/Control No.

09/911,892

Applicant(s)/Patent Under Exam

Donig et al.

Examiner

John Kim

Art Unit

1723

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
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x	B	5,311,899	5/1994	Isayama et al.		
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**NON-PATENT DOCUMENTS**

*	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages						
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	X						

<sup>\*</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.